

<b>Notice of References Cited</b>	Application/Control No. 10/702,170		Applicant(s)/Patent Under Reexamination INOUE, HITOSHI	
	Examiner Steven Kau		Art Unit 2625	Page 1 of 1

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*	B	US-5,369,499	11-1994	Yip, Kwok-leung	358/406
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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